

In the Abstract:

Please replace the abstract with the following amended abstract:

Abstract of the Disclosure

A test device for testing integrated circuits includes a lid and a base joined at a hinge and secured together with a latch. Within the base is a socket body that electrically connects the integrated circuit under test to the item the socket is mounted to (i.e. load board). Attached to the lid are bearing assemblies. An incline cam that may or may not include arresting points along the incline, rotates on the bearings which are attached to the lid. ~~A handle is attached to the cam. A pressure plate is attached to the cam.~~ The cam, which is attached to the handle, ~~provides a rotating means~~ translates rotational movement to vertical movement for lowering a pressure plate. ~~This device~~ ~~The means for lowering a pressure plate~~ may allow incremental lowering of a pressure plate by ~~means of the~~ by including stop points on the cam. ~~The base may include a sight groove for examination of the integrated circuit and internal socket parts.~~